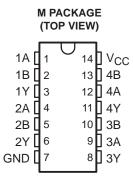
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- Controlled Baseline
 - One Assembly/Test Site, One Fabrication Site
- Extended Temperature Performance of Up To -55°C to 125°C
- Enhanced Diminishing Manufacturing Sources (DMS) Support
- Enhanced Product-Change Notification
- Qualification Pedigree[†]
- Buffered Inputs
- Typical Propagation Delay 7 ns at V_{CC} = 5 V, C_L = 15 pF, T_A = 25°C
- Fanout (Over Temperature Range)
 - Standard Outputs ... 10 LSTTL Loads
 - Bus Driver Outputs ... 15 LSTTL Loads
- † Component qualification in accordance with JEDEC and industry standards to ensure reliable operation over an extended temperature range. This includes, but is not limited to, Highly Accelerated Stress Test (HAST) or biased 85/85, temperature cycle, autoclave or unbiased HAST, electromigration, bond intermetallic life, and mold compound life. Such qualification testing should not be viewed as justifying use of this component beyond specified performance and environmental limits.

- Balanced Propagation Delay and Transition Times
- Significant Power Reduction Compared to LSTTL Logic ICs
- 2-V to 6-V V_{CC} Operation
- High Noise Immunity N_{IL} or N_{IH} = 30% of V_{CC} at V_{CC} = 5 V
- CMOS Input Compatibility, $I_l \le 1 \mu A$ at V_{OL} , V_{OH}



description/ordering information

The CD74HC08 logic gates utilize silicon-gate CMOS technology to achieve operating speeds similar to LSTTL gates, with the low power consumption of standard CMOS integrated circuits. All devices can drive 10 LSTTL loads.

ORDERING INFORMATION

TA	PACKAG	GE‡	ORDERABLE PART NUMBER	TOP-SIDE MARKING	
-40°C to 125°C	SOIC - M	Tape and reel	CD74HC08QM96EP	HC08QEP	
-55°C to 125°C	SOIC - M	Tape and reel	CD74HC08MM96EP§	HC08MEP	

[‡] Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

FUNCTION TABLE (each gate)

		,	,
	INP	UTS	OUTPUT
	Α	В	Υ
ľ	Н	Н	Н
	L	Χ	L
	X	L	L



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



[§] Product Preview

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logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage range, V_{CC} . Input clamp current, I_{IK} ($V_I < -0.5 \text{ V or } V_I > V_{CC} + 0.5 \text{ V}$) (see Note 1) Output clamp current, I_{OK} ($V_O < -0.5 \text{ V or } V_O > V_{CC} + 0.5 \text{ V}$) (see Note 1) Continuous output current, I_O ($V_O > -0.5 \text{ or } V_O < V_{CC} + 0.5 \text{ V}$) Continuous current through V_{CC} or GND	±20 mA ±20 mA ±25 mA
Package thermal impedance, θ _{JA} (see Note 2)	180°C/W
Maximum junction temperature, T _J	150°C
Lead temperature (during soldering):	
At distance $1/16 \pm 1/32$ inch $(1,59 \pm 0,79$ mm) from case for 10 s max	300°C
Storage temperature range, T _{sta}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

recommended operating conditions (see Note 3)

			MIN	NOM	MAX	UNIT	
Vсс	Supply voltage		2	5	6	V	
		V _{CC} = 2 V	1.5				
\vee_{IH}	High-level input voltage	V _{CC} = 4.5 V	3.15			V	
		VCC = 6 V	4.2				
		V _{CC} = 2 V			0.5		
\vee_{IL}	Low-level input voltage	V _{CC} = 4.5 V			1.35	V	
		V _{CC} = 6 V			1.8		
VI	Input voltage		0		VCC	V	
VO	Output voltage		0		VCC	V	
		V _{CC} = 2 V			1000		
$\Delta t/\Delta v$	Input transition rise/fall time	V _{CC} = 4.5 V			500	ns	
		V _{CC} = 6 V			400		
т.	Operating free-air temperature	Q suffix	-40		125	°C	
TA	Operating nee-all temperature	M suffix	-55		125		

NOTE 3: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



^{2.} The package thermal impedance is calculated in accordance with JESD 51-7.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

BABAMETER	7507.00	NIDITION O	lo	.,	T,	4 = 25°C	;	MIN MAX		UNIT	
PARAMETER	TEST COI	NDITIONS	(mA)	VCC	MIN	TYP	MAX	MIN	MAX		
			-0.02	2 V	1.9			1.9			
		CMOS loads	-0.02	4.5 V	4.4			4.4			
Voн	$V_I = V_{IH} \text{ or } V_{IL}$		-0.02	6 V	5.9			5.9		V	
		TTL loads CMOS loads	-4	4.5 V	3.98			3.7			
			-5.2	6 V	5.48			5.2			
			0.02	2 V			0.1		0.1	.1	
			CMOS loads	CMOS loads	0.02	4.5 V			0.1		0.1
VOL	VI = VIH or VIL		0.02	6 V			0.1		0.1	V	
			4	4.5 V			0.26		0.4		
		TTL loads	5.2	6 V			0.26		0.4		
lj	V _I = V _{CC} or GND			6 V			±0.1		±1	μΑ	
Icc	$V_I = V_{CC}$ or GND		0	6 V			2		40	μΑ	
C _i							10		10	pF	

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

DADAMETED	FROM	то	CONDITIONS	, , , , , , , , , , , , , , , , , , ,	T,	4 = 25°C	;	MANN	MAY	UNIT
PARAMETER	(INPUT)	(OUTPUT)	CONDITIONS	vcc	MIN	TYP	MAX	MIN	MAX	UNIT
				2 V			90		135	
	A == D	V	C _L = 50 pF	4.5 V			18		27	
^t pd	A or B	Y		6 V			15		23	ns
			C _L = 15 pF	5 V		7				
				2 V			75		110	
t _t	A or B	Y	C _L = 50 pF	4.5 V			15		22	ns
				6 V			13		19	

operating characteristics, $T_A = 25$ °C, $V_{CC} = 5V$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance per gate (see Note 4)	No load	37	pF

NOTE 4: C_{pd} is used to determine the dynamic power consumption, per gate.

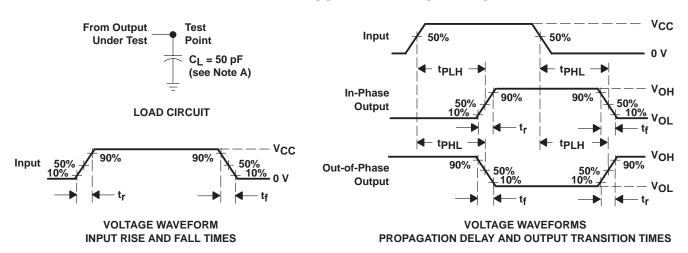
 $P_D^{pd} = V_{CC}^2 f_I (C_{pd} + C_L)$

 f_I = input frequency C_L = output load capacitance

V_{CC} = supply voltage



PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and test-fixture capacitance.

- B. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \ \Omega$, $t_\Gamma = 6 \ ns$, $t_f = 6 \ ns$.
- C. The outputs are measured one at a time, with one input transition per measurement.
- D. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS (3)	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
CD74HC08QM96EP	Active	Production	SOIC (D) 14	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HC08QEP
CD74HC08QM96EP.A	Active	Production	SOIC (D) 14	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HC08QEP
V62/04704-01XE	Active	Production	SOIC (D) 14	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HC08QEP

⁽¹⁾ Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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OTHER QUALIFIED VERSIONS OF CD74HC08-EP:

Catalog: CD74HC08

⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

PACKAGE OPTION ADDENDUM

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• Automotive : CD74HC08-Q1

Military: CD54HC08

NOTE: Qualified Version Definitions:

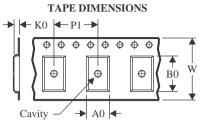
- Catalog TI's standard catalog product
- Automotive Q100 devices qualified for high-reliability automotive applications targeting zero defects
- Military QML certified for Military and Defense Applications

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





_	Tanana and a same and a same and a same and a same a s
A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD74HC08QM96EP	SOIC	D	14	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1

PACKAGE MATERIALS INFORMATION

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*All dimensions are nominal

Ì	Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
ı	CD74HC08QM96EP	SOIC	D	14	2500	340.5	336.1	32.0



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm, per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm, per side.
- 5. Reference JEDEC registration MS-012, variation AB.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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